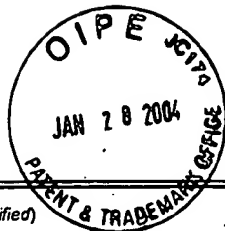
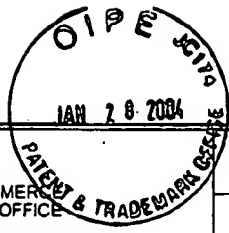


*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



FORM PTO 1449 (modified)		ATTY DOCKET NO. 00862.022172		APPLICATION NO. 09/819,669			
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) January 28, 2004		APPLICANT Yasuhiro SHIMADA et al.					
		FILING DATE March 29, 2001		GROUP 2881			
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
len		US-4,569,033	02/04/1986	Collins et al.	364	845	
		US-5,260,579	11/09/1993	Yasuda et al.	250	492.2	
		US-4,607,167	08/19/1986	Petric	250	492.2	
		US-6,072,251	06/06/2000	Markle	310	12	
		2002/0000766 A1	01/03/2002	Ono et al.	313	240	
		2001/0052576 A1	12/20/2001	Shimada et al.	250	492.1	
		2002/0008207 A1	01/24/1992	Muraki et al.	250	398	
		2002/0051111 A1	05/02/2002	Greene et al.	349	149	
len		2002/0005491 A1	01/17/2002	Yagi et al.	250	396	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
len		56-19402	05/08/1981	Japan	—	—	Y s
		2001-126651	05/11/2001	Japan	—	—	Abstract
len		6-44093	02/18/1994	Japan	—	—	Partial
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER len Marklen				DATE CONSIDERED 05-01-04			

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LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		FILING DATE March 29, 2001		GROUP 2881		
January 28, 2004						
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS SUBCLASS	FILING DATE IF APPROPRIATE
len		2002/0179855 A1	12/05/2002	Muraki	250 492.22	
		2002/0160311 A1	10/31/2002	Muraki et al.	430 926	
		US-6,566,644 B2	05/20/2003	Muraki	250 492.22	
		US-6,617,595 B1	09/09/2003	Okunuki	250 492.22	
		US-6,603,128 B2	08/05/2003	Maehara et al.	250 441.11	
		2003/0209673 A1	11/13/2003	Ono et al.	250 396 R	
		2003/0094584 A1	05/22/2003	Yui et al.	250 492.22	
		US-6,188,074 B1	02/13/2001	Satoh et al.	250 492.22	
len		2002/0009901 A1	01/24/2002	Maehara et al.	438 795	
FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER			DATE CONSIDERED			
len. MAY 28 2004			05-01-04			

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Sheet 2 of 2



FORM PTO 1449 (modified)		ATTY DOCKET NO. 00862.022172		APPLICATION NO. 09/819,669	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APPLICANT Yasuhiro SHIMADA et al.			
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		FILING DATE March 29, 2001		GROUP 2881	
August 7, 2003					
U.S. PATENT DOCUMENTS					
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS SUBCLASS FILING DATE IF APPROPRIATE
kn		US-4,354,111	10/12/1982	Williams et al.	250 396 R
		US-4,419,182	12/06/1983	Westerberg et al.	156 644
		US-4,742,234	05/03/1988	Feldman et al.	250 492.2
		US-5,534,311	07/09/1996	Shaw et al.	427 526
		US-6,184,850	**xwx.-99,-9999	Suzuki et al.	345 74
kn		US-6,566,664	05/20/2003	Muraki	250 492.2
FOREIGN PATENT DOCUMENTS					
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS SUBCLASS TRANSLATION YES/NO/ OR ABSTRACT
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)					
EXAMINER			DATE CONSIDERED		
k. MUYEN			05-01-04		

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